Sear	CH NOIE	25

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/685,996	SHIMADA ET AL.	
Examiner	Art Unit	
Hanh Phan	2613	

	SEAR	CHED	
Class	Subclass	Date	Examiner
398	202	01/19107	W
	208		
	212		
	214		
	182		
	186		
	195		
-	200		
	201		
	135		
	136		
	138		
	128,130		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u></u>			
	•			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East feared see	0/19/07	MP
attached print		
not in the file.		
ice seems.		
ipo sourcs.		
· ,		
•		
•		
	=	
		<del></del>